

Keynote: cost-efficient reliability for Edge-AI chips

Jenihhin, Maksim; Taheri, Mahdi; Cherezova, Natalia; Ahmadilivani, Mohammad Hasan; Selg, Hardi; Jutman, Artur; Shibin, Konstantin; Tsertov, Anton; Devadze, Sergei; Kodamanchili, Rama Mounika; Rafiq, Ahsan; Raik, Jaan; Daneshtalab, Masoud 2024 IEEE 25th Latin American Test Symposium (LATS) 2024 / 2 p <https://doi.org/10.1109/LATS62223.2024.10534610> [Article at Scopus](#)

On-chip sensors data collection and analysis for SoC health management

Shibin, Konstantin; Jenihhin, Maksim; Jutman, Artur; Devadze, Sergei; Tsertov, Anton 2023 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT) 2023 / 6 p <https://doi.org/10.1109/DFT59622.2023.10313562>

Special session: in-field ML-assisted intermittent fault localization and management in RISC-V SoCs

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